

TC74VHC10F, TC74VHC10FN, TC74VHC10FT

Triple 3-Input NAND Gate

The TC74VHC10 is an advanced high speed CMOS 3-INPUT NAND GATE fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent Bipolar Schottky TTL while maintaining the CMOS low power dissipation.

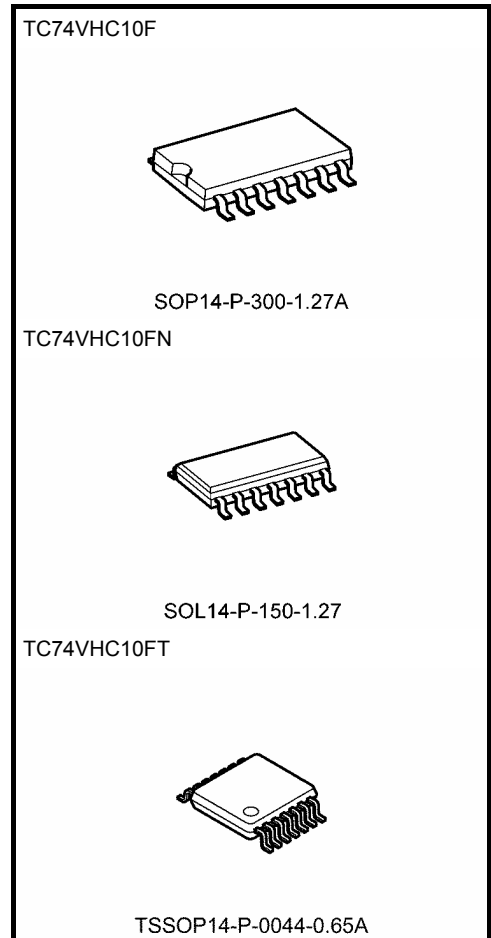
The internal circuit is composed of 3 stages including buffer output, which provide high noise immunity and stable output.

An input protection circuit ensures that 0 to 5.5 V can be applied to the input pins without regard to the supply voltage. This device can be used to interface 5 V to 3 V systems and two supply systems such as battery back up. This circuit prevents device destruction due to mismatched supply and input voltages.

Features

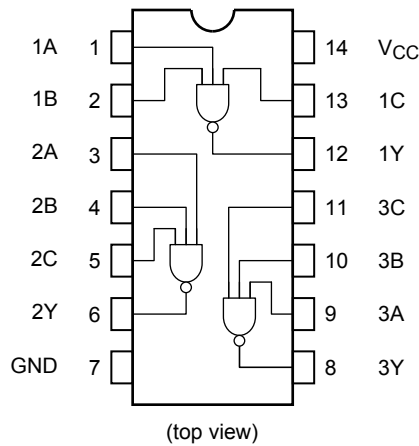
- High speed: $t_{pd} = 3.9 \text{ ns (typ.)}$ at $V_{CC} = 5 \text{ V}$
- Low power dissipation: $I_{CC} = 2 \mu\text{A (max)}$ at $T_a = 25^\circ\text{C}$
- High noise immunity: $V_{NIH} = V_{NIL} = 28\% V_{CC} \text{ (min)}$
- Power down protection is provided on all inputs.
- Balanced propagation delays: $t_{pLH} \approx t_{pHL}$
- Wide operating voltage range: $V_{CC} \text{ (opr)} = 2 \text{ to } 5.5 \text{ V}$
- Pin and function compatible with 74ALS10

Note: xxxFN (JEDEC SOP) is not available in Japan.

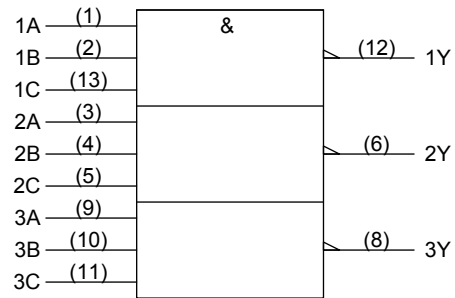


Weight	
SOP14-P-300-1.27A	: 0.18 g (typ.)
SOL14-P-150-1.27	: 0.12 g (typ.)
TSSOP14-P-0044-0.65A	: 0.06 g (typ.)

Pin Assignment



IEC Logic Symbol



Truth Table

A	B	C	Y
L	X	X	H
X	L	X	H
X	X	L	H
H	H	H	L

X: Don't care

Absolute Maximum Ratings (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage range	V_{CC}	-0.5 to 7.0	V
DC input voltage	V_{IN}	-0.5 to 7.0	V
DC output voltage	V_{OUT}	-0.5 to $V_{CC} + 0.5$	V
Input diode current	I_{IK}	-20	mA
Output diode current	I_{OK}	±20	mA
DC output current	I_{OUT}	±25	mA
DC V_{CC} /ground current	I_{CC}	±50	mA
Power dissipation	P_D	180	mW
Storage temperature	T_{stg}	-65 to 150	°C

Note: Exceeding any of the absolute maximum ratings, even briefly, lead to deterioration in IC performance or even destruction.

Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings and the operating ranges.

Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Operating Ranges (Note)

Characteristics	Symbol	Rating	Unit
Supply voltage	V_{CC}	2.0 to 5.5	V
Input voltage	V_{IN}	0 to 5.5	V
Output voltage	V_{OUT}	0 to V_{CC}	V
Operating temperature	T_{opr}	-40 to 85	°C
Input rise and fall time	dt/dv	0 to 100 ($V_{CC} = 3.3 \pm 0.3$ V) 0 to 20 ($V_{CC} = 5 \pm 0.5$ V)	ns/V

Note: The operating ranges must be maintained to ensure the normal operation of the device.
Unused inputs must be tied to either V_{CC} or GND.

Electrical Characteristics

DC Characteristics

Characteristics	Symbol	Test Condition	V_{CC} (V)	$T_a = 25^\circ\text{C}$			$T_a = -40$ to 85°C		Unit	
				Min	Typ.	Max	Min	Max		
High-level input voltage	V_{IH}	—	2.0 3.0 to 5.5	1.50 $V_{CC} \times 0.7$	— —	— —	1.50 $V_{CC} \times 0.7$	— —	V	
Low-level input voltage	V_{IL}	—	2.0 3.0 to 5.5	— —	— —	0.50 $V_{CC} \times 0.3$	— —	0.50 $V_{CC} \times 0.3$	V	
High-level output voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -50 \mu\text{A}$	2.0	1.9	2.0	—	1.9	—	V
				3.0	2.9	3.0	—	2.9	—	
			$I_{OH} = -4 \text{ mA}$ $I_{OH} = -8 \text{ mA}$	3.0	2.58	—	—	2.48	—	
				4.5	3.94	—	—	3.80	—	
Low-level output voltage	V_{OL}	$V_{IN} = V_{IH}$	$I_{OL} = 50 \mu\text{A}$	2.0	—	0.0	0.1	—	0.1	V
				3.0	—	0.0	0.1	—	0.1	
				4.5	—	0.0	0.1	—	0.1	
			$I_{OL} = 4 \text{ mA}$ $I_{OL} = 8 \text{ mA}$	3.0	—	—	0.36	—	0.44	
4.5	—	—		0.36	—	0.44				
Input leakage current	I_{IN}	$V_{IN} = 5.5 \text{ V}$ or GND	0 to 5.5	—	—	± 0.1	—	± 1.0	μA	
Quiescent supply current	I_{CC}	$V_{IN} = V_{CC}$ or GND	5.5	—	—	2.0	—	20.0	μA	

AC Characteristics (input: $t_r = t_f = 3$ ns)

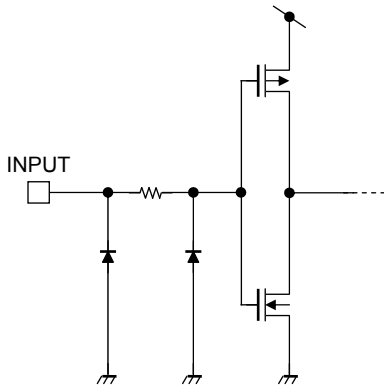
Characteristics	Symbol	Test Condition		Ta = 25°C			Ta = -40 to 85°C		Unit	
		V _{CC} (V)	C _L (pF)	Min	Typ.	Max	Min	Max		
Propagation delay time	t _{pLH}	—	3.3 ± 0.3	15	—	5.7	8.4	1.0	10.0	ns
				50	—	8.2	11.9	1.0	13.5	
	t _{pHL}	5.0 ± 0.5	15	—	3.9	5.9	1.0	7.0		
			50	—	5.4	7.9	1.0	9.0		
Input capacitance	C _{IN}	—		—	4	10	—	10	pF	
Power dissipation capacitance	C _{PD}	(Note)		—	17	—	—	—	pF	

Note: C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation:

$$I_{CC(opr)} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}/3 \text{ (per gate)}$$

Input Equivalent Circuit



Package Dimensions

SOP14-P-300-1.27A

Unit: mm

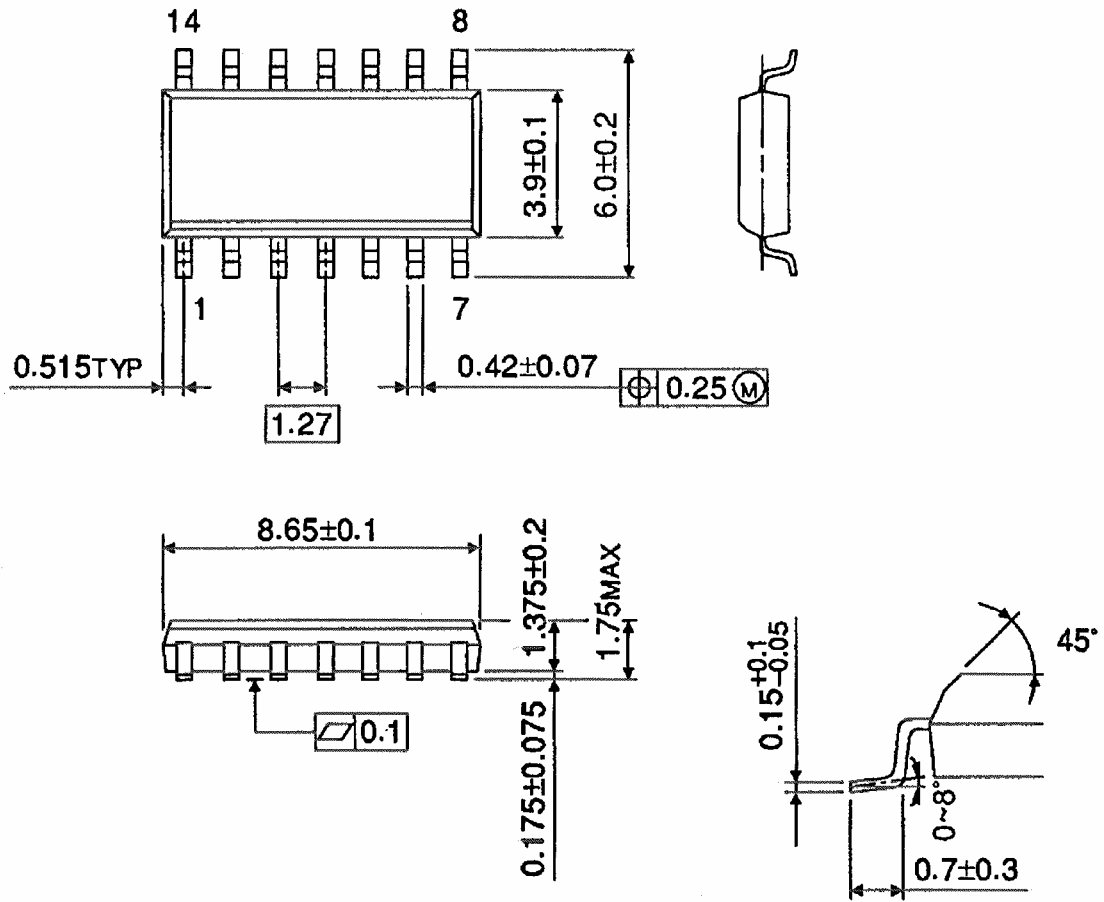


Weight: 0.18 g (typ.)

Package Dimensions (Note)

SOL14-P-150-1.27

Unit : mm



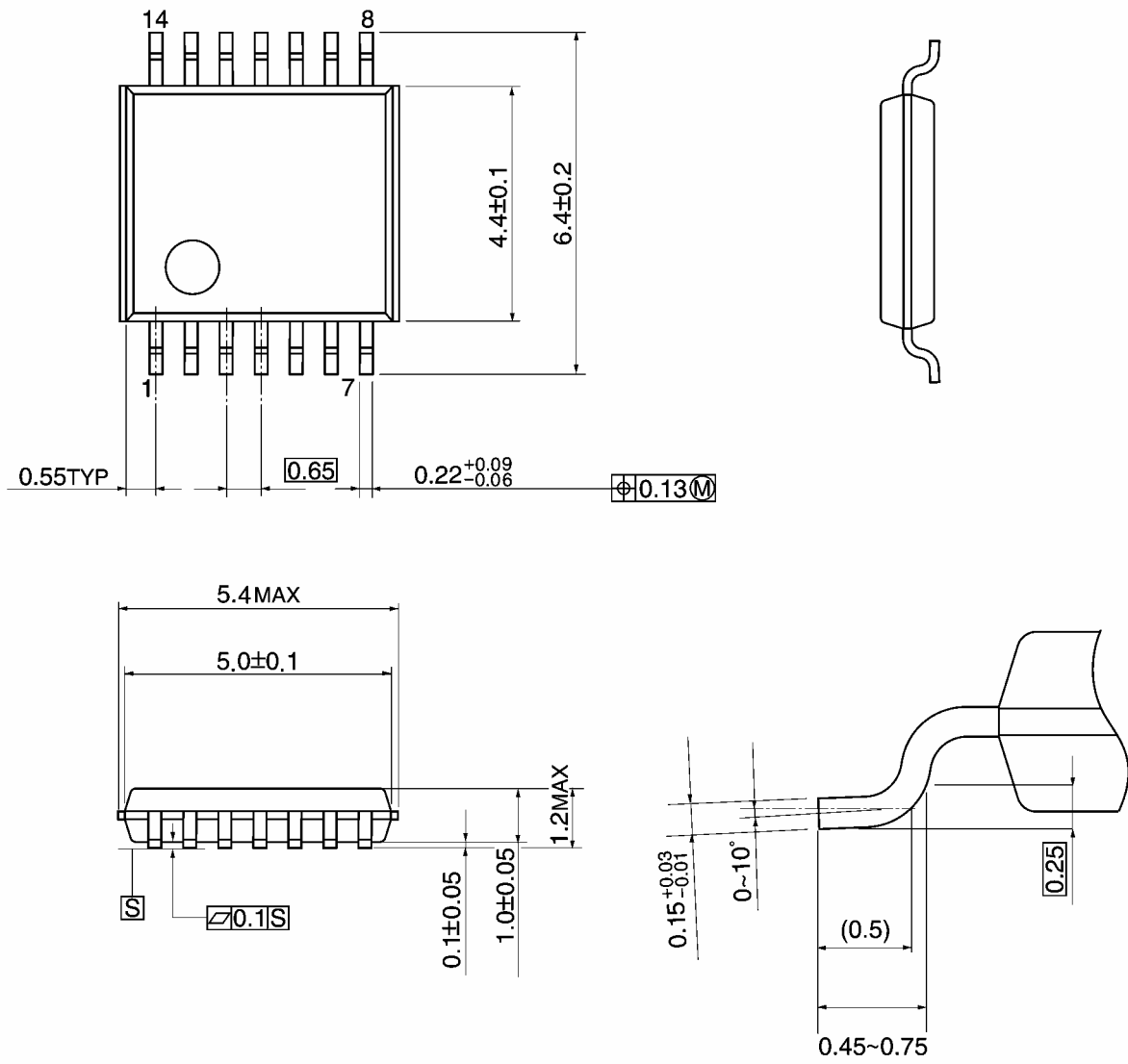
Note: This package is not available in Japan.

Weight: 0.12 g (typ.)

Package Dimensions

TSSOP14-P-0044-0.65A

Unit: mm



Weight: 0.06 g (typ.)
d

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20070701-EN GENERAL

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